

NX3008NBKW

30 V, 350 mA N-channel Trench MOSFET Rev. 1 — 2 August 2011

Product data sheet

Product profile

1.1 General description

N-channel enhancement mode Field-Effect Transistor (FET) in a small SOT323 (SC-70) Surface-Mounted Device (SMD) plastic package using Trench MOSFET technology.

1.2 Features and benefits

- Very fast switching
- Low threshold voltage
- Trench MOSFET technology
- ESD protection up to 2 kV
- AEC-Q101 qualified

1.3 Applications

- Relay driver
- High-speed line driver

- Low-side loadswitch
- Switching circuits

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j = 25 °C	-	-	30	V
V_{GS}	gate-source voltage		-8	-	8	V
I _D	drain current	$V_{GS} = 4.5 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}$	<u>[1]</u> _	-	350	mA
Static characteristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V; } I_D = 350 \text{ mA;}$ $T_j = 25 \text{ °C}$	-	1	1.4	Ω

^[1] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm².



2. Pinning information

Table 2. Pinning information

	_	,		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	S	source	3	D
3	D	drain	1	G S 017aaa255

3. Ordering information

Table 3. Ordering information

Type number	Package			
	Name	Description	Version	
NX3008NBKW	SC-70	plastic surface-mounted package; 3 leads	SOT323	

4. Marking

Table 4. Marking codes

Type number	Marking code[1]
NX3008NBKW	AA%

^{[1] % =} placeholder for manufacturing site code

5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Mir	Max	Unit
V_{DS}	drain-source voltage	T _j = 25 °C	-	30	V
V _{GS}	gate-source voltage		-8	8	V
I _D	drain current	$V_{GS} = 4.5 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}$	<u>[1]</u> _	350	mA
		V _{GS} = 4.5 V; T _{amb} = 100 °C	<u>[1]</u> _	230	mA
I _{DM}	peak drain current	$T_{amb} = 25 \text{ °C}$; single pulse; $t_p \le 10 \text{ µs}$	-	1.4	Α
P _{tot}	total power dissipation	T _{amb} = 25 °C	[2] _	260	mW
			<u>[1]</u> _	310	mW
		T _{sp} = 25 °C	-	830	mW
Tj	junction temperature		-55	150	°C
T _{amb}	ambient temperature		-55	150	°C
T _{stg}	storage temperature		-65	150	°C
Source-drain	diode				
Is	source current	T _{amb} = 25 °C	<u>[1]</u> _	300	mA
ESD maximu	m rating				
V _{ESD}	electrostatic discharge voltage	НВМ	[3]	2000	V

 $[\]label{eq:condition} \textbf{[1]} \quad \text{Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm2.}$

^[2] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.

^[3] Measured between all pins.

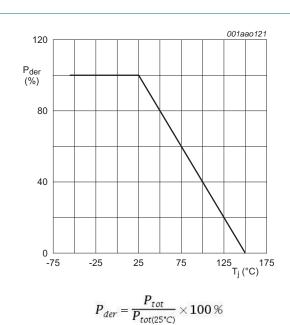


Fig 1. Normalized total power dissipation as a function of junction temperature

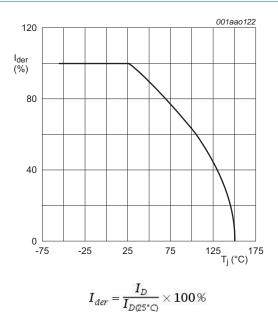
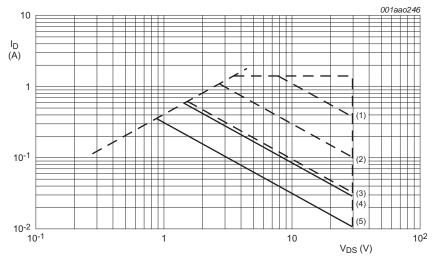


Fig 2. Normalized continuous drain current as a function of junction temperature



I_{DM} is a single pulse

- (1) $t_p = 1 \text{ ms}$
- (2) $t_p = 10 \text{ ms}$
- (3) $t_p = 100 \text{ ms}$
- (4) DC; $T_{sp} = 25 \, ^{\circ}\text{C}$
- (5) DC; $T_{amb} = 25 \text{ °C}$; 1 cm² drain mounting pad

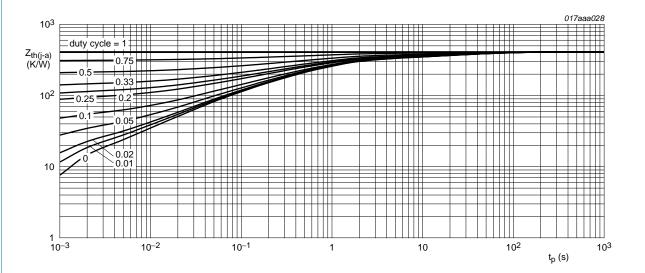
Fig 3. Safe operating area; junction to ambient; continuous and peak drain currents as a function of drain-source voltage

6. Thermal characteristics

Table 6. Thermal characteristics

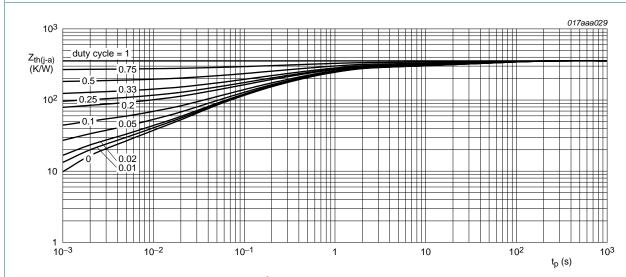
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	<u>[1]</u> -	310	370	K/W
			[2] _	260	300	K/W
R _{th(j-sp)}	thermal resistance from junction to solder point		-	-	115	K/W

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm².



FR4 PCB, standard footprint

Fig 4. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, mounting pad for drain 1 cm²

Fig 5. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

7. Characteristics

Table 7. Characteristics

Table 7.	Characteristics	O	P. 41	T .		
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
	aracteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
V_{GSth}	gate-source threshold voltage	$I_D = 250 \mu A; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	0.6	0.9	1.1	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	10	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.2	1	μΑ
		$V_{GS} = -8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.2	1	μΑ
		$V_{GS} = 4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	-	nΑ
		$V_{GS} = -4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	-	nΑ
		$V_{GS} = 2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	1	-	nΑ
		$V_{GS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	1	-	nΑ
R _{DSon}	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 350 \text{ mA}; T_j = 25 \text{ °C}$	-	1	1.4	Ω
	resistance	$V_{GS} = 4.5 \text{ V}; I_D = 350 \text{ mA}; T_j = 150 \text{ °C}$	-	1.8	2.5	Ω
		$V_{GS} = 2.5 \text{ V}; I_D = 200 \text{ mA}; T_j = 25 \text{ °C}$	-	1.4	2.1	Ω
		$V_{GS} = 1.8 \text{ V}; I_D = 10 \text{ mA}; T_j = 25 ^{\circ}\text{C}$	-	2	2.8	Ω
9 _{fs}	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 350 \text{ mA}; T_j = 25 \text{ °C}$	-	310	-	mS
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$V_{DS} = 15 \text{ V}; I_D = 350 \text{ mA}; V_{GS} = 4.5 \text{ V};$	-	0.52	0.68	nC
Q_{GS}	gate-source charge	T _j = 25 °C	-	0.17	-	nC
Q_{GD}	gate-drain charge		-	0.08	-	nC
C _{iss}	input capacitance	$V_{DS} = 15 \text{ V}$; f = 1 MHz; $V_{GS} = 0 \text{ V}$;	-	34	50	pF
C _{oss}	output capacitance	T _j = 25 °C	-	6.5	-	pF
C _{rss}	reverse transfer capacitance		-	2.2	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 20 \text{ V}; R_L = 250 \Omega; V_{GS} = 4.5 \text{ V};$	-	15	30	ns
t _r	rise time	$R_{G(ext)} = 6 \Omega; T_j = 25 °C$	-	11	-	ns
t _{d(off)}	turn-off delay time		-	69	138	ns
t _f	fall time		-	19	-	ns
Source-d	rain diode					
V _{SD}	source-drain voltage	$I_S = 350 \text{ mA}; V_{GS} = 0 \text{ V}; T_i = 25 \text{ °C}$	0.47	0.85	1.2	V

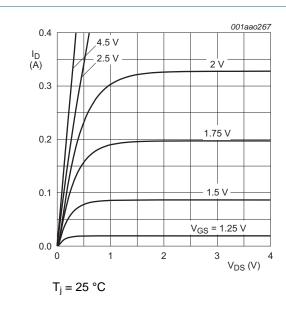
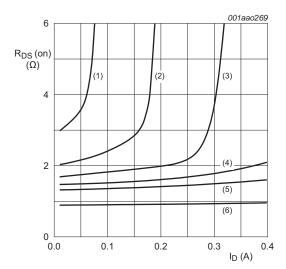


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values



T_i = 25 °C

(1) $V_{GS} = 1.5 \text{ V}$

(2) $V_{GS} = 1.75 \text{ V}$

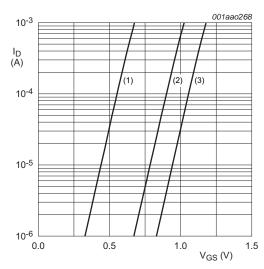
(3) $V_{GS} = 2.0 \text{ V}$

(4) $V_{GS} = 2.25 \text{ V}$

(5) $V_{GS} = 2.5 \text{ V}$

(6) $V_{GS} = 4.5 \text{ V}$

Fig 8. Drain-source on-state resistance as a function of drain current; typical values



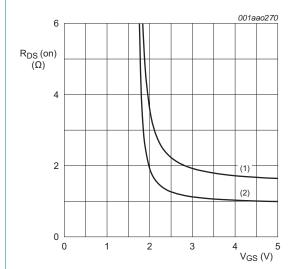
 $T_j = 25 \, ^{\circ}C; \, V_{DS} = 5 \, V$

(1) minimum values

(2) typical values

(3) maximum values

Fig 7. Sub-threshold drain current as a function of gate-source voltage

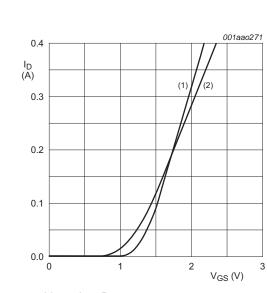


 $I_D = 350 \text{ mA}$

(1) $T_i = 150 \, ^{\circ}C$

(2) $T_i = 25 \, ^{\circ}C$

Fig 9. Drain-source on-state resistance as a function of gate-source voltage; typical values

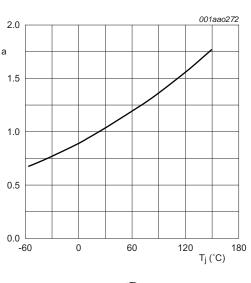


 $V_{DS} > I_D \; x \; R_{DSon}$

(1)
$$T_j = 25 \, ^{\circ}C$$

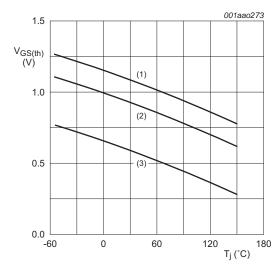
(2)
$$T_j = 150 \, ^{\circ}\text{C}$$

Fig 10. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$

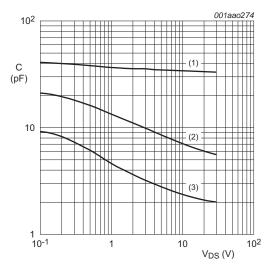
Fig 11. Normalized drain-source on-state resistance as a function of junction temperature; typical values



 $I_D = 0.25 \text{ mA}; V_{DS} = V_{GS}$

- (1) maximum values
- (2) typical values
- (3) minimum values

Fig 12. Gate-source threshold voltage as a function of junction temperature



 $f = 1 \text{ MHz}; V_{GS} = 0 \text{ V}$

(1)C_{iss}

(2)Coss

(3)C_{rss}

Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

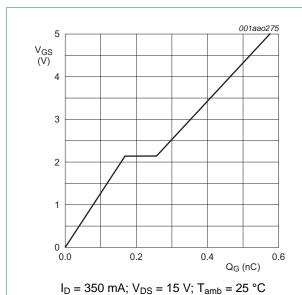


Fig 14. Gate-source voltage as a function of gate charge; typical values

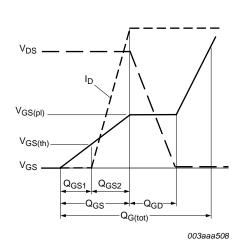
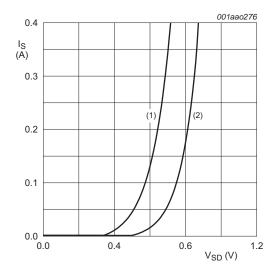


Fig 15. Gate charge waveform definitions



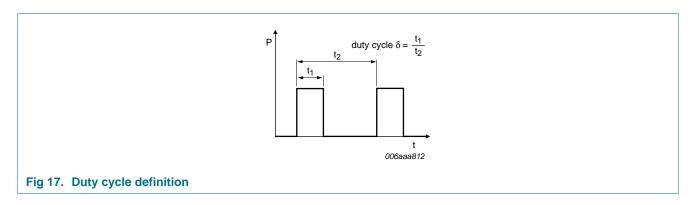
 $V_{GS} = 0 V$

(1) $T_j = 150 \, ^{\circ}\text{C}$

(2) $T_i = 25 \, ^{\circ}C$

Fig 16. Source current as a function of source-drain voltage; typical values

8. Test information



8.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

9. Package outline

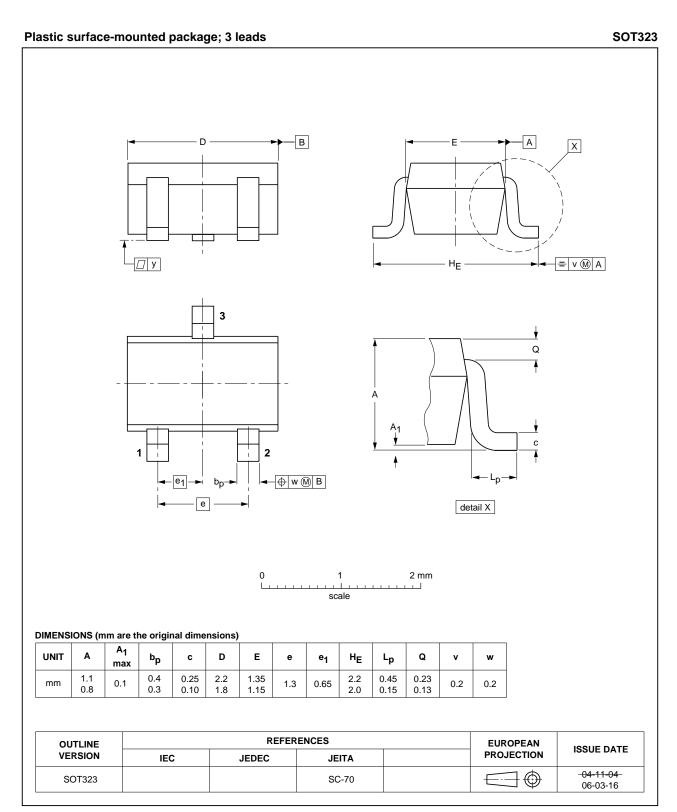
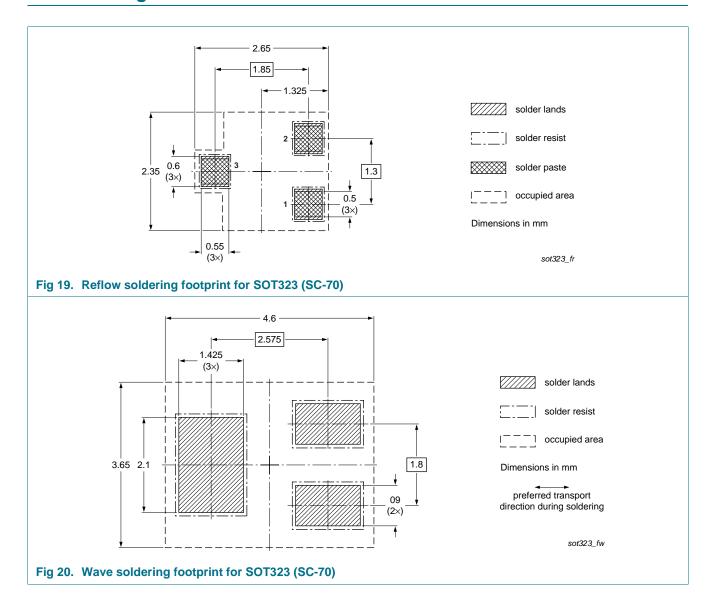


Fig 18. Package outline SOT323 (SC-70)

10. Soldering





11. Revision history

Table 8. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
NX3008NBKW v.1	20110802	Product data sheet	-	-

12. Legal information

12.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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NX3008NBKW

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NX3008NBKW

30 V, 350 mA N-channel Trench MOSFET

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NX3008NBKW

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